

**In the Claims:**

1. (original) A semiconductor body having at least one integrated circuit formed at a surface thereof, the at least one integrated circuit comprising:

core functional logic;

a terminal buffer coupled in a single path between the core functional logic and a terminal pad, for forwarding a signal along the signal path;

a load test switch for selectively connecting a load terminal to the terminal pad;

a first test switch for selectively connecting an input of the terminal buffer to a first test terminal;

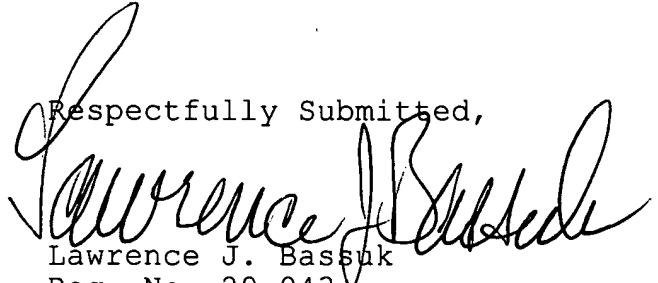
a second test switch for selectively connecting an output of the terminal buffer to a second test terminal; and

control circuitry for controlling the operation of the load test switch and the first and second test switches so as to be open in normal operation, and so as to be selectively closed in a test mode.

2-34. (canceled)

Applicant respectfully requests examination of this application.

Respectfully Submitted,

A handwritten signature in cursive script, appearing to read "Lawrence J. Bassuk".

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